

<b>Search Notes</b>  	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10521547	AOYAMA ET AL.
	<b>Examiner</b> Tran, Len	<b>Art Unit</b> 1725

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
219	93, 86.31, 89	03/24/07	LT
	updated search	7/31/07	LT

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
search notes attached	03/24/07	
updated search	7/31/07	LT

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
219	searched subclasses	7/31/07	LT